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LP	International Electron D	evices Meet	ing, 26, 8	3, 1, IEEE, September	1998.						
1	Kern Rim, et al., "Chara Symposium On VLSI T						i N- and PMO	SFE	:IS",	200)2
	Gregory Scott, et al., "N	IMOS Drive	Current F	Reduction Caused by	ransisto	or La	vout and Trei	nch	solai	tion	
	Induced Stress", Interna	ational Electr	on Devic	es Meeting, 34.4.1, IE	EE, Sep	tem	ber 1999.				
	F. Ootsuka, et al., "A H									ale	
	System-on-a-Chip App Shinya Ito, et al., "Mech										
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	K. Ota, et al., "Novel Lo Electron Devices Meeti	cally Straine	d Chann	el Technique for high	Performa	ance	55nm CMOS	6", In	terna	atior	nal
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	6 406 072 PJ	6/18/2002	Lee						
	6,406,973 B1								
	6,281,532 B1	8/28/2001	Doyle et al.						
 	5,683,934	11/4/97	Candelaria						
	6,368,931 B1	4/9/2002	Kuhn, et al.						
	5,310,446	5/10/94	Konishi et al.	<u> </u>					
	4,853,076 8/1/89 US 2002/0090791 A1 7/11/2002 US 2002/0074598 A1 6/20/2002 6,509,618 B2 1/21/03 . 6,476,462 B2 11/5/2002		Tsaur et al.	<u>. </u>					
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	6,362,082 B1	3/26/2002	Doyle et al.						
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	5,565,697	10/15/96	Asakawa et al.						
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	US 2002/0086472 A1	7/4/2002	Roberds et al.						
	6,521,964 B1	2/18/2003	Jan et al.						
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10	5,081,513	1/14/1992	Jackson, et al.						
1	3,602,841	8/31/1971	McGroddy						
	6,531,740	3/11/2003	Bosco, et al.	<u> </u>					
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	6,498,358 12/24/2002 6,493,497 12/10/2002 6,403,975 6/11/2002 6,361,885 3/26/2002		Lach, et al.				· · · · · · · · · · · · · · · · · · ·		
			Ramdani, et al.						
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			Chou						
- . 	6,255,169	7/3/2001	Li, et al.						
	6,246,095	6/12/2001	Brady, et al.						
	6,165,383	12/26/2000	Chou				·		
	6,133,071	10/17/2000	Nagai						
	6,046,464	4/4/2000	Schetzina			<u> </u>			
-V	6,025,280	2/15/2000	Brady, et al.						
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10	5,940,736	8/17/1999	Brady, et al.				
	5,880,040	3/9/1999	Sun, et al.				
	5,861,651	1/19/1999	Brasen, et al.				
1	5,679,965	10/21/1997	Schetzina				
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	5,561,302 10/1/1996		Candelaria				
	5,471,948 12/5/1995		Burroughes, et al.				
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	5,391,510 2/21/1995 5,371,399 12/6/1994 5,108,843 4/28/1992		Hsu, et al.				
			Burroughes, et al.				
			Ohtaka, et al.				
	5,060,030	10/22/1991	Hoke				
	4,958,213	9/18/1990	Eklund, et al.				
	4,665,415	5/12/1987	Esaki, et al.				
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}	6,261,964	7/17/2001	Wang Wu, et al.				
	6,221,735	4/24/2001	Manley, et al.				
	6,117,722 9/12/2000		Wuu, et al.				
	6,107,143	8/22/2000	Park, et al.			<u> </u>	
	6,090,684	7/18/2000	Ishitsuka, et al.				
	6,066,545	5/23/2000	Doshi, et al.				
	6,008,126	12/28/1999	Leedy			<u> </u>	
	5,946,559	8/31/1999	Leedy				
	5,840,593	11/24/1998	Leedy	 			
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LP	5,557,122	9/17/1996	Shrivastava, et al.						
1	5,354,695	10/11/1994	Leedy						
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